

## FIR12N60APG-VB Datasheet

# N-Channel 650V (D-S) Super Junction Power MOSFET

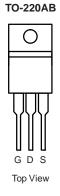
PRODUCT SUMMARY				
V <sub>DS</sub> (V) at T <sub>J</sub> max.	700			
R <sub>DS(on)</sub> at 25 °C (Ω)	V <sub>GS</sub> = 10 V 0.5			
Q <sub>g</sub> max. (nC)	25			
Q <sub>gs</sub> (nC)	2.0			
Q <sub>gd</sub> (nC)	2.7			
Configuration	Single			

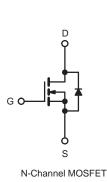
## **FEATURES**

- Low figure-of-merit (FOM) Ron x Qa
- Low input capacitance (Ciss)
- · Reduced switching and conduction losses
- Ultra low gate charge (Qg)
- Avalanche energy rated (UIS)

### **APPLICATIONS**

- Server and telecom power supplies
- Switch mode power supplies (SMPS)
- Power factor correction power supplies (PFC)
- Lighting
  - High-intensity discharge (HID)
  - Fluorescent ballast lighting
- Industrial





ABSOLUTE MAXIMUM RATINGS (T <sub>C</sub> =	= 25 °C, unl	ess otherwis	se noted)		
PARAMETER			SYMBOL	LIMIT	UNIT
Drain-Source Voltage			V <sub>DS</sub>	650	v
Gate-Source Voltage			V <sub>GS</sub>	± 30	v
Continuous Drain Current (T 150 °C)	V <sub>GS</sub> at 10 V	T <sub>C</sub> = 25 °C T <sub>C</sub> = 100 °C		9	
Continuous Drain Current (T <sub>J</sub> = 150 °C)	V <sub>GS</sub> at 10 V	T <sub>C</sub> = 100 °C		6	А
Pulsed Drain Current <sup>a</sup>			I <sub>DM</sub>	21	
Linear Derating Factor				1.5	W/°C
Single Pulse Avalanche Energy <sup>b</sup>			E <sub>AS</sub>	186	mJ
Maximum Power Dissipation			P <sub>D</sub>	123	W
Operating Junction and Storage Temperature Range			T <sub>J</sub> , T <sub>stg</sub>	-55 to +150	°C
Drain-Source Voltage Slope $T_J = 125 \text{ °C}$		dV/dt	50	1//20	
Reverse Diode dV/dt <sup>d</sup>			4.5	V/ns	
Soldering Recommendations (Peak Temperature) <sup>c</sup> for 10 s				300	°C

#### Notes

a. Repetitive rating; pulse width limited by maximum junction temperature. b.  $V_{DD} = 50 \text{ V}$ , starting  $T_J = 25 \text{ °C}$ , L = 28.2 mH,  $R_g = 25 \Omega$ ,  $I_{AS} = 3.5 \text{ A}$ . c. 1.6 mm from case. d.  $I_{SD} \le I_D$ , dI/dt = 100 A/µs, starting  $T_J = 25 \text{ °C}$ .



THERMAL RESISTANCE RATINGS						
PARAMETER	SYMBOL	TYP.	MAX.	UNIT		
Maximum Junction-to-Ambient	R <sub>thJA</sub>	-	63	°C/W		
Maximum Junction-to-Case (Drain)	R <sub>thJC</sub>	-	0.6	C/vv		

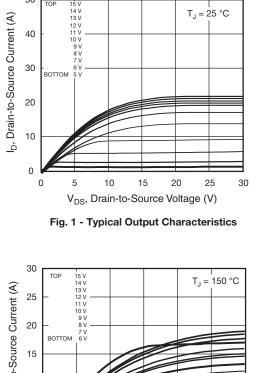
PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT
Static				•	•	•	
Drain-Source Breakdown Voltage	V <sub>DS</sub>	V <sub>GS</sub> =	= 0 V, I <sub>D</sub> = 250 μA	650	-	-	V
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Reference	e to 25 °C, I <sub>D</sub> = 1 mA	-	0.65	-	V/°C
Gate-Source Threshold Voltage (N)	V <sub>GS(th)</sub>	V <sub>DS</sub> =	= V <sub>GS</sub> , I <sub>D</sub> = 250 μΑ	2	-	4	V
		$V_{GS} = \pm 20 V$		-	-	± 100	nA
Gate-Source Leakage	I <sub>GSS</sub>	$V_{GS} = \pm 30 \text{ V}$		-	-	± 1	μA
			$V_{DS} = 600 \text{ V}, \text{ V}_{GS} = 0 \text{ V}$		-	1	-
Zero Gate Voltage Drain Current	I <sub>DSS</sub>		/, V <sub>GS</sub> = 0 V, T <sub>J</sub> = 125 °C	-	-	10	μA
Drain-Source On-State Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V	$I_D = 4 A$	-	0.50	-	Ω
Forward Transconductance	g <sub>fs</sub>	V <sub>DS</sub>	= 30 V, I <sub>D</sub> = 4 A	-	16	-	S
Dynamic		-1		1	1	1	
Input Capacitance	C <sub>iss</sub>		V <sub>GS</sub> = 0 V,	-	360	-	_
Output Capacitance	C <sub>oss</sub>		V <sub>DS</sub> = 100 V,	-	25	-	
Reverse Transfer Capacitance	C <sub>rss</sub>		f = 1 MHz		12	-	1
Effective Output Capacitance, Energy Related <sup>a</sup>	C <sub>o(er)</sub>	- $V_{DS} = 0 V \text{ to } 520 V, V_{GS} = 0 V$		-	45	-	pF
Effective Output Capacitance, Time Related <sup>b</sup>	C <sub>o(tr)</sub>			-	62	-	1
Total Gate Charge	Qg				25		
Gate-Source Charge	Q <sub>gs</sub>	V <sub>GS</sub> = 10 V I <sub>D</sub> = 4 A, V <sub>DS</sub> = 520 V		-	2.0	-	nC
Gate-Drain Charge	Q <sub>gd</sub>			-	2.7	-	
Turn-On Delay Time	t <sub>d(on)</sub>			-	25	-	- ns
Rise Time	t <sub>r</sub>	Voo	$\label{eq:VDD} \begin{array}{l} V_{\text{DD}} = 520 \ \text{V}, \ I_{\text{D}} = 4 \ \text{A}, \\ V_{\text{GS}} = 10 \ \text{V}, \ R_{g} = 9.1 \ \Omega \end{array}$		55	-	
Turn-Off Delay Time	t <sub>d(off)</sub>				70	-	
Fall Time	t <sub>f</sub>				40	-	
Gate Input Resistance	Rg	f = 1 MHz, open drain		-	3.5	-	Ω
Drain-Source Body Diode Characteristic	s						
Continuous Source-Drain Diode Current	I <sub>S</sub>	MOSFET symbol showing the integral reverse p - n junction diode		-	-	7	
Pulsed Diode Forward Current	I <sub>SM</sub>			-	-	18	A
Diode Forward Voltage	V <sub>SD</sub>	T <sub>J</sub> = 25 °C, I <sub>S</sub> = 4 A, V <sub>GS</sub> = 0 V		-	-	1.5	V
Reverse Recovery Time	t <sub>rr</sub>	$T_{J} = 25 \text{ °C}, I_{F} = I_{S} = 4 \text{ A},$ dl/dt = 100 A/µs, V <sub>R</sub> = 400 V		-	190	-	ns
Reverse Recovery Charge	Q <sub>rr</sub>			-	2.3	-	μC
Reverse Recovery Current	I <sub>BRM</sub>			<u> </u>	10		A

#### Notes

a.  $C_{oss(er)}$  is a fixed capacitance that gives the same energy as  $C_{oss}$  while  $V_{DS}$  is rising from 0 % to 80 %  $V_{DSS}$ . b.  $C_{oss(tr)}$  is a fixed capacitance that gives the same charging time as  $C_{oss}$  while  $V_{DS}$  is rising from 0 % to 80 %  $V_{DSS}$ .

50





## TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

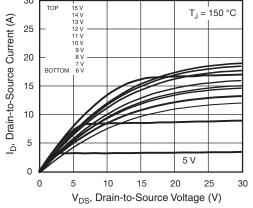


Fig. 2 - Typical Output Characteristics

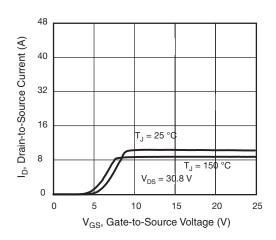


Fig. 3 - Typical Transfer Characteristics

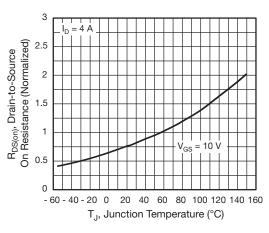


Fig. 4 - Normalized On-Resistance vs. Temperature

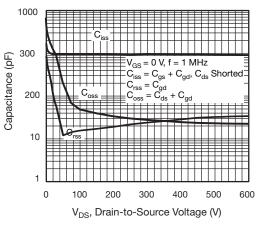


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

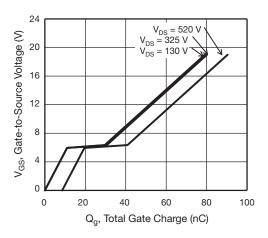


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage



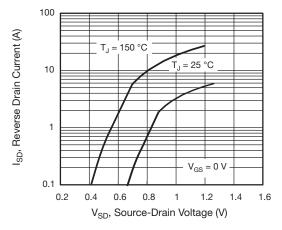


Fig. 7 - Typical Source-Drain Diode Forward Voltage



Fig. 8 - Maximum Safe Operating Area

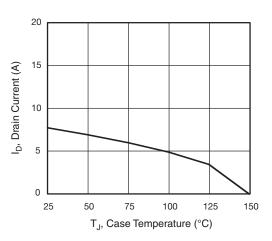


Fig. 9 - Maximum Drain Current vs. Case Temperature

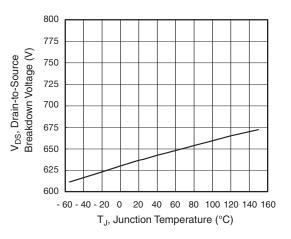


Fig. 10 - Temperature vs. Drain-to-Source Voltage

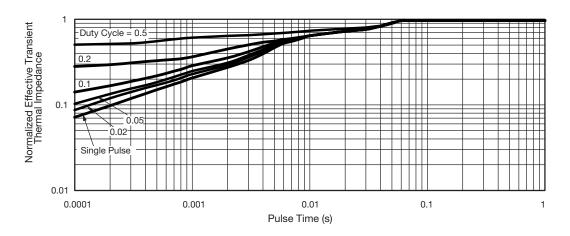


Fig. 11 - Normalized Thermal Transient Impedance, Junction-to-Case



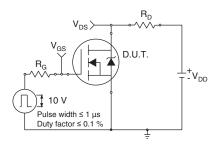


Fig. 12 - Switching Time Test Circuit

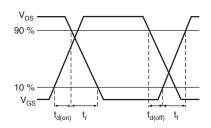


Fig. 13 - Switching Time Waveforms

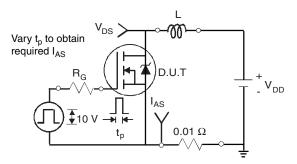


Fig. 14 - Unclamped Inductive Test Circuit



Fig. 15 - Unclamped Inductive Waveforms

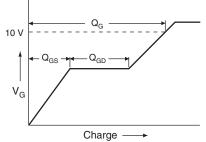


Fig. 16 - Basic Gate Charge Waveform

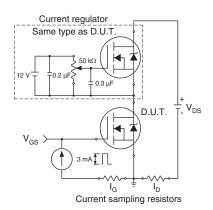
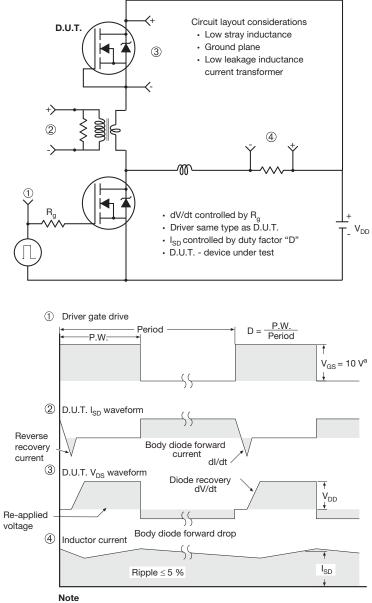


Fig. 17 - Gate Charge Test Circuit



Peak Diode Recovery dV/dt Test Circuit

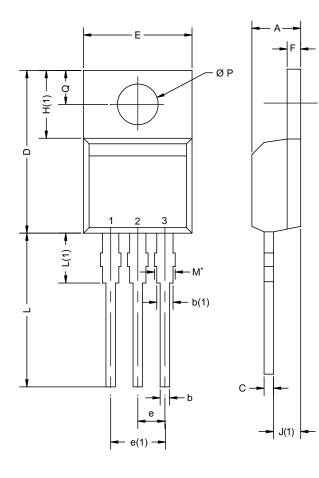


a.  $V_{GS} = 5$  V for logic level devices

Fig. 18 - For N-Channel



## **TO-220AB**



	MILLIMETERS		INCHES		
DIM.	MIN.	MAX.	MIN.	MAX.	
А	4.25	4.65	0.167	0.183	
b	0.69	1.01	0.027	0.040	
b(1)	1.20	1.73	0.047	0.068	
С	0.36	0.61	0.014	0.024	
D	14.85	15.49	0.585	0.610	
Е	10.04	10.51	0.395	0.414	
е	2.41	2.67	0.095	0.105	
e(1)	4.88	5.28	0.192	0.208	
F	1.14	1.40	0.045	0.055	
H(1)	6.09	6.48	0.240	0.255	
J(1)	2.41	2.92	0.095	0.115	
L	13.35	14.02	0.526	0.552	
L(1)	3.32	3.82	0.131	0.150	
ØΡ	3.54	3.94	0.139	0.155	
Q	2.60	3.00	0.102	0.118	
ECN: X12-0208-Rev. N, 08-Oct-12 DWG: 5471					

#### Notes

\* M = 1.32 mm to 1.62 mm (dimension including protrusion) Heatsink hole for HVM



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